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May 2015

FQD2P40

P-Channel QFET® MOSFET

-400 V, -1.56 A, 6.5 Ω

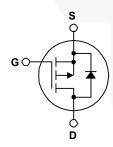
Description

This P-Channel enhancement mode power MOSFET is produced using Fairchild Semiconductor's proprietary planar stripe and DMOS technology. This advanced MOSFET technology has been especially tailored to reduce on-state resistance, and to provide superior switching performance • Low Crss (Typ. 6.5 pF) and high avalanche energy strength. These devices are suitable for switched mode power supplies, audio amplifier, DC motor control, and variable switching power applications.. • RoHS Compliant

Features

- -1.56 A, -400 V, $R_{DS(on)}$ = 6.5 Ω (Max.) @ V_{GS} = -10 V, $I_D = -0.78 A$
- Low Gate Charge (Typ. 10 nC)
- 100% Avalanche Tested





Absolute Maximum Ratings T_C = 25°C unless otherwise noted.

Symbol	Parameter		FQD2P40TM	Unit
V_{DSS}	Drain-Source Voltage		-400	V
I _D	Drain Current - Continuous (T _C = 25°C)		-1.56	Α
	- Continuous (T _C = 100°C)		-0.98	Α
I _{DM}	Drain Current - Pulsed	(Note 1)	-6.24	Α
V _{GSS}	Gate-Source Voltage		± 30	V
E _{AS}	Single Pulsed Avalanche Energy	(Note 2)	120	mJ
I _{AR}	Avalanche Current	(Note 1)	-1.56	Α
E _{AR}	Repetitive Avalanche Energy	(Note 1)	3.8	mJ
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	-4.5	V/ns
P_{D}	Power Dissipation (T _A = 25°C) *		2.5	W
	Power Dissipation (T _C = 25°C)		38	W
	- Derate above 25°C		0.3	W/°C
T _J , T _{STG}	Operating and Storage Temperature Range		-55 to +150	°C
T _L	Maximum lead temperature for soldering, 1/8" from case for 5 seconds		300	°C

Thermal Characteristics

Symbol	Parameter	FQD2P40TM	Unit
$R_{\theta JC}$	Thermal Resistance, Junction to Case, Max.	3.29	
Ъ	Thermal Resistance, Junction to Ambient (Minimum Pad of 2-oz Copper), Max.	110	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (*1 in ² Pad of 2-oz Copper), Max.	50	

Package Marking and Ordering Information

Part Number	Top Mark	Package	Packing Method	Reel Size	Tape Width	Quantity
FQD2P40TM	FQD2P40	D-PAK	Tape and Reel	330 mm	16 mm	2500 units

Electrical Characteristics

T_C = 25°C unless otherwise noted.

Symbol	Parameter	Test Conditions	Mi	n. Typ.	Max.	Unit
Off Cha	aracteristics					
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = -250 \mu\text{A}$	-40	0		V
ΔBV _{DSS} / ΔT _J	Breakdown Voltage Temperature Coefficient	I _D = -250 μA, Referenced to 25°C		-		V/°C
Inee	Zana Cata Valtana Duain Courset	V _{DS} = -400 V, V _{GS} = 0 V			-1	μА
	Zero Gate Voltage Drain Current	V _{DS} = -320 V, T _C = 125°C			-10	μΑ
I _{GSSF}	Gate-Body Leakage Current, Forward	V _{GS} = -30 V, V _{DS} = 0 V			-100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	V _{GS} = 30 V, V _{DS} = 0 V			100	nA
On Cha	racteristics					
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = -250 \mu\text{A}$	-3.)	-5.0	V
R _{DS(on)}	Static Drain-Source On-Resistance	V _{GS} = -10 V, I _D = -0.78 A		5.0	6.5	Ω
9 _{FS}	Forward Transconductance	$V_{DS} = -50 \text{ V}, I_{D} = -0.78 \text{ A}$		1.26		S
C _{iss}	Input Capacitance Output Capacitance	V_{DS} = -25 V, V_{GS} = 0 V, f = 1.0 MHz		270 45	350 60	pF pF
C _{rss}	Reverse Transfer Capacitance			6.5	8.5	pF
	ing Characteristics			9	20	
t _{d(on)} t _r	Turn-On Delay Time Turn-On Rise Time	$V_{DD} = -200 \text{ V}, I_{D} = -2.0 \text{ A},$		33	30 75	ns
	Turn-Off Delay Time	$R_G = 25 \Omega$		22	55	ns ns
t _{d(off)}	Turn-Off Fall Time	(No	te 4)	25	60	ns
Q _g	Total Gate Charge	V - 200 V I - 2 0 A		10	13	nC
Q _{gs}	Gate-Source Charge	$V_{DS} = -320 \text{ V}, I_{D} = -2.0 \text{ A},$ $V_{GS} = -10 \text{ V}$ (Note 4)		2.1		nC
Q _{gd}	Gate-Drain Charge			5.5		nC
		,				
	Source Diode Characteristics an				1	
l _S	Maximum Continuous Drain-Source Diode Forward Current				-1.56	A
I _{SM}	Maximum Pulsed Drain-Source Diode F				-6.24	A
V _{SD}	Drain-Source Diode Forward Voltage	V _{GS} = 0 V, I _S = -1.56 A			-5.0	V
t _{rr}	Reverse Recovery Time	$V_{GS} = 0 \text{ V}, I_{S} = -2.0 \text{ A},$		250	-	ns

- **Notes:** 1. Repetitive rating : pulse-width limited by maximum junction temperature. 2. L = 86 mH, I_{AS} = -1.56 A, V_{DD} = -50 V, R_{G} = 25 Ω , starting T_{J} = 25°C. 3. I_{SD} ≤ -2.0 A, di/dt ≤ 200 A/ μ s, V_{DD} ≤ BV $_{DSS}$, starting T_{J} = 25°C. 4. Essentially independent of operating temperature.

Reverse Recovery Charge

μC

0.85

 $dI_F / dt = 100 A/\mu s$

Typical Characteristics

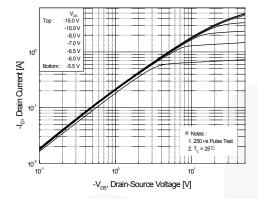


Figure 1. On-Region Characteristics

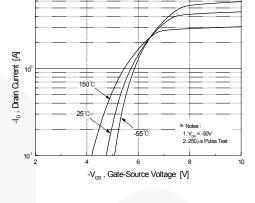


Figure 2. Transfer Characteristics

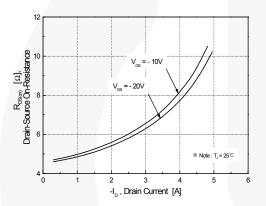


Figure 3. On-Resistance Variation vs.
Drain Current and Gate Voltage

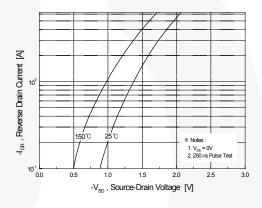


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

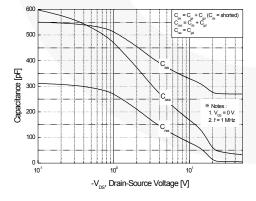


Figure 5. Capacitance Characteristics

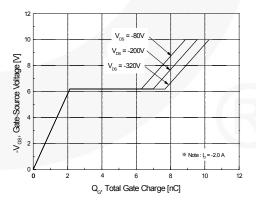


Figure 6. Gate Charge Characteristics

Typical Characteristics (Continued)

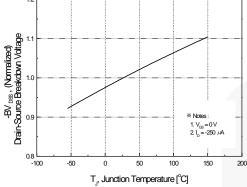
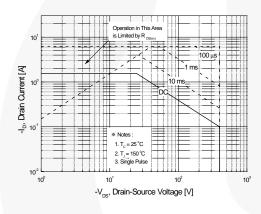


Figure 7. Breakdown Voltage Variation vs. Temperature

Figure 8. On-Resistance Variation vs. Temperature



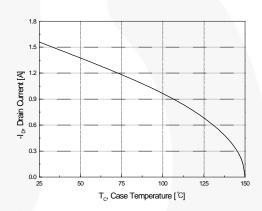


Figure 9. Maximum Safe Operating Area

Figure 10. Maximum Drain Current vs. Case Temperature

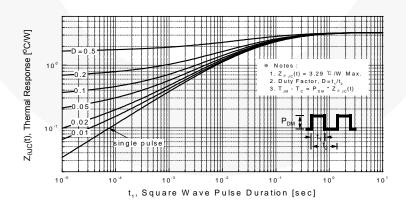


Figure 11. Transient Thermal Response Curve

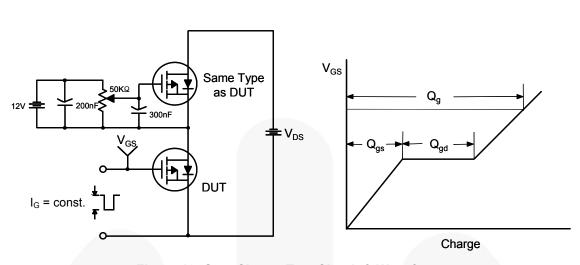


Figure 12. Gate Charge Test Circuit & Waveform

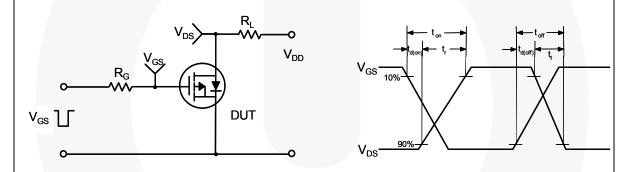


Figure 13. Resistive Switching Test Circuit & Waveforms

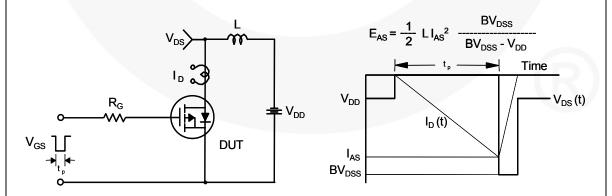
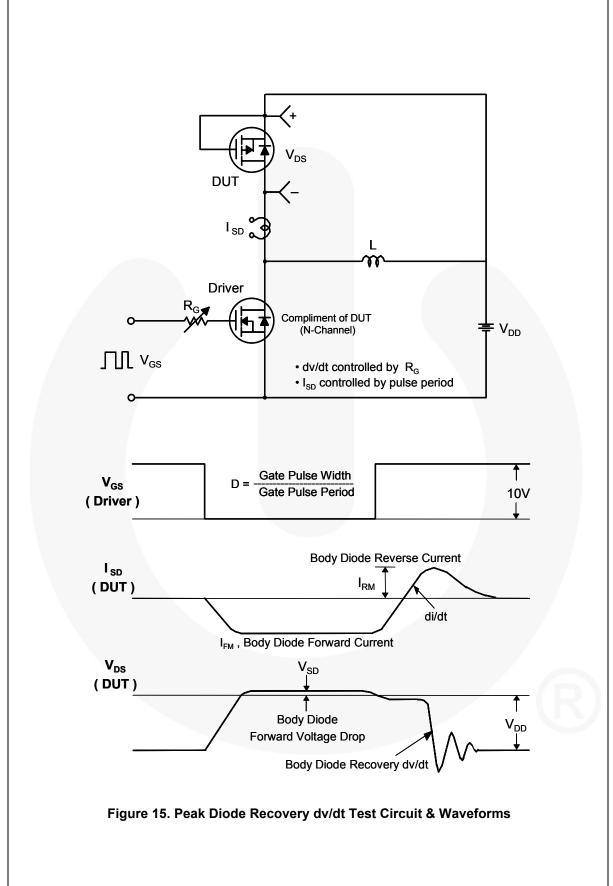


Figure 14. Unclamped Inductive Switching Test Circuit & Waveforms





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